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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, QSPI, UART/USART, USB OTG
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	96
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x12b
Oscillator Type	Internal
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/pcf52258ag80

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  - Up to 80 MHz processor core frequency
  - 40 MHz or 33 MHz peripheral bus frequency
  - Sixteen general-purpose, 32-bit data and address registers
  - Implements ColdFire ISA_A with extensions to support the user stack pointer register and four new instructions for improved bit processing (ISA_A+)
  - Enhanced Multiply-Accumulate (EMAC) unit with four 32-bit accumulators to support 16×16 → 32 or 32×32 → 48 operations
  - Cryptographic Acceleration Unit (CAU)
    - Tightly-coupled coprocessor to accelerate software-based encryption and message digest functions
    - Support for DES, 3DES, AES, MD5, and SHA-1 algorithms
- System debug support
  - Real-time trace for determining dynamic execution path
  - Background debug mode (BDM) for in-circuit debugging (DEBUG_B+)
  - Real-time debug support, with six hardware breakpoints (4 PC, 1 address and 1 data) configurable into a 1- or 2-level trigger
- On-chip memories
  - Up to 64 KB dual-ported SRAM on CPU internal bus, supporting core, DMA, and USB access with standby power supply support for the first 16 KB
  - Up to 512 KB of interleaved flash memory supporting 2-1-1-1 accesses
- Power management
  - Fully static operation with processor sleep and whole chip stop modes
  - Rapid response to interrupts from the low-power sleep mode (wake-up feature)
  - Clock enable/disable for each peripheral when not used (except backup watchdog timer)
  - Software controlled disable of external clock output for low-power consumption
- FlexCAN 2.0B module
  - Based on and includes all existing features of the Freescale TouCAN module
  - Full implementation of the CAN protocol specification version 2.0B
    - Standard data and remote frames (up to 109 bits long)
    - Extended data and remote frames (up to 127 bits long)
    - Zero to eight bytes data length
    - Programmable bit rate up to 1 Mbit/s
  - Flexible message buffers (MBs), totalling up to 16 message buffers of 0–8 byte data length each, configurable as Rx or Tx, all supporting standard and extended messages
  - Unused MB space can be used as general purpose RAM space
  - Listen-only mode capability
  - Content-related addressing
  - No read/write semaphores
  - Three programmable mask registers: global for MBs 0–13, special for MB14, and special for MB15
  - Programmable transmit-first scheme: lowest ID or lowest buffer number
  - Time stamp based on 16-bit free-running timer
  - Global network time, synchronized by a specific message
  - Maskable interrupts
- Universal Serial Bus On-The-Go (USB OTG) dual-mode host and device controller
  - Full-speed / low-speed host controller
  - USB 1.1 and 2.0 compliant full-speed / low speed device controller
  - 16 bidirectional end points

  - DMA or FIFO data stream interfaces
  - Low power consumption
  - OTG protocol logic
- Fast Ethernet controller (FEC)
  - 10/100 BaseT/TX capability, half duplex or full duplex
  - On-chip transmit and receive FIFOs
  - Built-in dedicated DMA controller
  - Memory-based flexible descriptor rings
- Mini-FlexBus
  - External bus interface available on 144 pin packages
  - Supports glueless interface with 8-bit ROM/flash/SRAM/simple slave peripherals. Can address up to 2 MB of addresses
  - 2 chip selects ($\overline{\text{FB\_CS}}$[1:0])
  - Non-multiplexed mode: 8-bit dedicated data bus, 20-bit address bus
  - Multiplexed mode: 16-bit data and 20-bit address bus
  - FB_CLK output to support synchronous memories
  - Programmable base address, size, and wait states to support slow peripherals
  - Operates at up to 40 MHz (bus clock) in 1:2 mode or up to 80 MHz (core clock) in 1:1 mode
- Three universal asynchronous/synchronous receiver transmitters (UARTs)
  - 16-bit divider for clock generation
  - Interrupt control logic with maskable interrupts
  - DMA support
  - Data formats can be 5, 6, 7, or 8 bits with even, odd, or no parity
  - Up to two stop bits in 1/16 increments
  - Error-detection capabilities
  - Modem support includes request-to-send (RTS) and clear-to-send (CTS) lines for two UARTs
  - Transmit and receive FIFO buffers
- Two I2C modules
  - Interchip bus interface for EEPROMs, LCD controllers, A/D converters, and keypads
  - Fully compatible with industry-standard I2C bus
  - Master and slave modes support multiple masters
  - Automatic interrupt generation with programmable level
- Queued serial peripheral interface (QSPI)
  - Full-duplex, three-wire synchronous transfers
  - Up to three chip selects available
  - Master mode operation only
  - Programmable bit rates up to half the CPU clock frequency
  - Up to 16 pre-programmed transfers
- Fast analog-to-digital converter (ADC)
  - Eight analog input channels
  - 12-bit resolution
  - Minimum 1.125 μs conversion time
  - Simultaneous sampling of two channels for motor control applications
  - Single-scan or continuous operation
  - Optional interrupts on conversion complete, zero crossing (sign change), or under/over low/high limit

  - Pre-divider capable of dividing the clock source frequency into the PLL reference frequency range
  - System can be clocked from PLL or directly from crystal oscillator or relaxation oscillator
  - Low power modes supported
  - 2^n ($0 \le n \le 15$) low-power divider for extremely low frequency operation
- Interrupt controller
  - Uniquely programmable vectors for all interrupt sources
  - Fully programmable level and priority for all peripheral interrupt sources
  - Seven external interrupt signals with fixed level and priority
  - Unique vector number for each interrupt source
  - Ability to mask any individual interrupt source or all interrupt sources (global mask-all)
  - Support for hardware and software interrupt acknowledge (IACK) cycles
  - Combinatorial path to provide wake-up from low-power modes
- DMA controller
  - Four fully programmable channels
  - Dual-address transfer support with 8-, 16-, and 32-bit data capability, along with support for 16-byte (4×32-bit) burst transfers
  - Source/destination address pointers that can increment or remain constant
  - 24-bit byte transfer counter per channel
  - Auto-alignment transfers supported for efficient block movement
  - Bursting and cycle-steal support
  - Software-programmable DMA requests for the UARTs (3) and 32-bit timers (4)
  - Channel linking support
- Reset
  - Separate reset in and reset out signals
  - Seven sources of reset:
    - Power-on reset (POR)
    - External
    - Software
    - Watchdog
    - Loss of clock / loss of lock
    - Low-voltage detection (LVD)
    - JTAG
  - Status flag indication of source of last reset
- Chip configuration module (CCM)
  - System configuration during reset
  - Selects one of six clock modes
  - Configures output pad drive strength
  - Unique part identification number and part revision number
- General purpose I/O interface
  - Up to 56 bits of general purpose I/O on 100-pin package
  - Up to 96 bits of general purpose I/O on 144-pin package
  - Bit manipulation supported via set/clear functions
  - Programmable drive strengths
  - Unused peripheral pins may be used as extra GPIO
- JTAG support for system level board testing

Figure 3 shows the pinout configuration for the 100 LQFP.

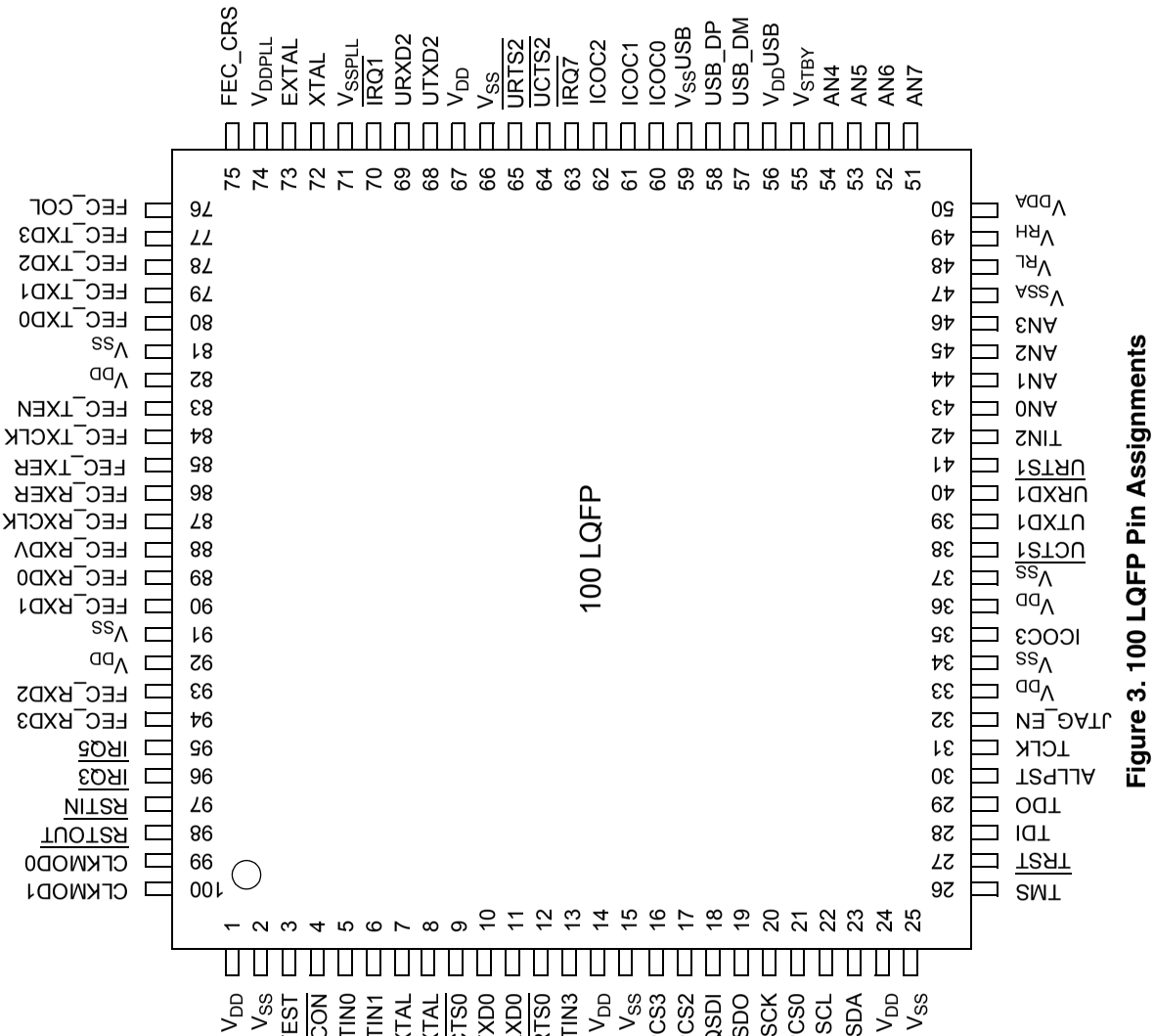


Figure 3. 100 LQFP Pin Assignments

Table 3. Pin Functions by Primary and Alternate Purpose (continued)

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
Mode Selection	$\overline{\text{RCON}}$/$\overline{\text{EZPCS}}$	—	—	—	N/A	N/A	Pull-Up	E4	10	4
	CLKMOD[1:0]	—	—	—	N/A	N/A	Pull-Down	D4, D5	144, 143	100, 99
QSPI	QSPI_CS3	SYNCA	USB_DP_PDOWN	PQS6	PSRR[7]	PDSR[7]	—	G4	22	16
	QSPI_CS2	SYNCB	USB_DM_PDOWN	PQS5	PSRR[6]	PDSR[6]	—	G3	23	17
	QSPI_CS0	I2C_SDA0	UCTS1	PQS3	PSRR[4]	PDSR[4]	Pull-Up[6]	H4	27	21
	QSPI_CLK/ EZPCK	I2C_SCL0	URTS1	PQS2	PSRR[3]	PDSR[3]	Pull-Up[6]	H3	26	20
QSPI	QSPI_DIN/ EZPD	I2C_SDA1	URXD1	PQS1	PSRR[2]	PDSR[2]	Pull-Up[6]	G2	24	18
	QSPI_DOUT/EZPQ	I2C_SCL1	UTXD1	PQS0	PSRR[1]	PDSR[1]	Pull-Up[6]	G1	25	19
Reset[7]	$\overline{\text{RSTI}}$	—	—	—	N/A	N/A	Pull-Up[7]	A3	141	97
	$\overline{\text{RSTO}}$	—	—	—	Low	High	—	A2	142	98
Test	TEST	—	—	—	N/A	N/A	Pull-Down	B1	9	3
Timer 3, 16-bit	GPT3	—	PWM7	PTA3	PSRR[23]	PDSR[23]	Pull-Up[8]	M7	58	35
Timer 2, 16-bit	GPT2	—	PWM5	PTA2	PSRR[22]	PDSR[22]	Pull-Up[8]	J10	95	62
Timer 1, 16-bit	GPT1	—	PWM3	PTA1	PSRR[21]	PDSR[21]	Pull-Up[8]	J11	94	61
Timer 0, 16-bit	GPT0	—	PWM1	PTA0	PSRR[20]	PDSR[20]	Pull-Up[8]	F12	93	60
Timer 3, 32-bit	DTIN3	DTOUT3	PWM6	PTC3	PSRR[19]	PDSR[19]	—	F4	19	13
Timer 2, 32-bit	DTIN2	DTOUT2	PWM4	PTC2	PSRR[18]	PDSR[18]	—	J8	65	42

Table 3. Pin Functions by Primary and Alternate Purpose (continued)

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
Timer 1, 32-bit	DTIN1	DTOUT1	PWM2	PTC1	PSRR[17]	PDSR[17]	—	C1	12	6
Timer 0, 32-bit	DTIN0	DTOUT0	PWM0	PTC0	PSRR[16]	PDSR[16]	—	D2	11	5
UART 0	UCTS0	—	USB_VBUSE	PUA3	PSRR[11]	PDSR[11]	—	E2	15	9
	URTS0	—	USB_VBUSD	PUA2	PSRR[10]	PDSR[10]	—	F3	18	12
	URXD0	—	—	PUA1	PSRR[9]	PDSR[9]	—	F2	17	11
	UTXD0	—	—	PUA0	PSRR[8]	PDSR[8]	—	F1	16	10
UART 1	UCTS1	SYNCA	URXD2	PUB3	PSRR[15]	PDSR[15]	—	K7	61	38
	URTS1	SYNCB	UTXD2	PUB2	PSRR[14]	PDSR[14]	—	M8	64	41
	URXD1	I2C_SDA1	—	PUB1	PSRR[13]	PDSR[13]	Pull-Up[6]	L8	63	40
	UTXD1	I2C_SCL1	—	PUB0	PSRR[12]	PDSR[12]	Pull-Up[6]	K8	62	39
UART 2	UCTS2	I2C_SCL1	USB_VBUSCHG	PUC3	PSRR[27]	PDSR[27]	Pull-Up[6]	E11	97	64
	URTS2	I2C_SDA1	USB_VBUSDIS	PUC2	PSRR[26]	PDSR[26]	Pull-Up[6]	E10	98	65
	URXD2	CANRX	—	PUC1	PSRR[25]	PDSR[25]	—	C10	102	69
	UTXD2	CANTX	—	PUC0	PSRR[24]	PDSR[24]	—	D10	101	68
USB OTG	USB_DM	—	—	—	N/A	N/A	—	H11	80	57
	USB_DP	—	—	—	N/A	N/A	—	H12	81	58
	USB_VDD	—	—	—	N/A	N/A	—	J9	79	56
	USB_VSS	—	—	—	N/A	N/A	—	H9	82	59

Table 3. Pin Functions by Primary and Alternate Purpose (continued)

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
Mini-FlexBus[9]	FB_ALE	$\overline{\text{FB\_CS1}}$	—	PAS2	PSRRL[20]	PDSRL[20]	—	K3	37	—
	FB_AD[7:0]	—	—	PTE[7:0]	PSRRL[7:0]	PDSRL[7:0]	—	J2, J1, K4, K6, J6, M6, L6, L7	34–36; 53–57	—
	FB_AD[15:8]	—	—	PTF[7:0]	PSRRL[15:8]	PDSRL[15:8]	—	C4, B2, C3, C2, D3, E3, J3, J4	136, 2–6, 32–33	—
	FB_AD[19:16]	—	—	PTG[3:0]	PSRRL[19:16]	PDSRL[19:16]	—	B6, C6, D6, C5	130–133	—
	$\overline{\text{FB\_CS0}}$	—	—	PTG5	PSRRL[21]	PDSRL[21]	—	M5	52	—
	FB_R/$\overline{\text{W}}$	—	—	PTG7	PSRRL[31]	PDSRL[31]	—	M4	45	—
	$\overline{\text{FB\_OE}}$	—	—	PTG6	PSRRL[30]	PDSRL[30]	—	B5	137	—
	FB_D7	CANRX	—	PTH5	PSRRL[29]	PDSRL[29]	—	A5	138	—
	FB_D6	CANTX	—	PTH4	PSRRL[28]	PDSRL[28]	—	A4	139	—
	FB_D5	I2C_SCL1	—	PTH3	PSRRL[27]	PDSRL[27]	Pull-Up[6]	B4	140	—
	FB_D4	I2C_SDA1	—	PTH2	PSRRL[26]	PDSRL[26]	Pull-Up[6]	B3	1	—
	FB_D3	USB_ VBUSD	—	PTH1	PSRRL[25]	PDSRL[25]	—	L4	46	—
	FB_D2	USB_ VBUSE	—	PTH0	PSRRL[24]	PDSRL[24]	—	K5	47	—
	FB_D1	SYNCA	—	PTH7	PSRRL[23]	PDSRL[23]	—	L5	50	—
	FB_D0	SYNCB	—	PTH6	PSRRL[22]	PDSRL[22]	—	J5	51	—
Standby Voltage	VSTBY	—	—	—	N/A	N/A	—	J12	78	55
VDD[10]	VDD	—	—	—	N/A	N/A	—	E5–E8; F5; G5; H5–7; J7	7; 20; 30; 48; 59; 92; 100; 115; 125; 135	1; 14; 24; 33; 36; 67; 82; 92

Table 7. Current Consumption in Low-Power Mode, Code From SRAM[1,2,3]

Mode	8 MHz (Typ)	16 MHz (Typ)	64 MHz (Typ)	80 MHz (Typ)	Unit	Symbol
Stop mode 3 (Stop 11)[4]	0.090				mA	I_{DD}
Stop mode 2 (Stop 10)[4]	7					
Stop mode 1 (Stop 01)[4,5]	9	10	15	17		
Stop mode 0 (Stop 00)[5]	9	10	15	17		
Wait / Doze	13	18	42	50		
Run	16	21	55	65		

1 All values are measured with a 3.3 V power supply. Tests performed at room temperature.
2 Refer to the Power Management chapter in the *MCF52259 Reference Manual* for more information on low-power modes.
3 CLKOUT, PST/DDATA signals, and all peripheral clocks except UART0 off before entering low-power mode. CLKOUT is disabled. Code executed from SRAM with flash memory shut off by writing 0x0 to the FLASHBAR register.
4 See the description of the Low-Power Control Register (LPCR) in the *MCF52259 Reference Manual* for more information on stop modes 0–3.
5 Results are identical to STOP 00 for typical values because they only differ by CLKOUT power consumption. CLKOUT is already disabled in this instance prior to entering low-power mode.

2.3 Thermal Characteristics

Table 8 lists thermal resistance values.

Table 8. Thermal Characteristics

	Characteristic		Symbol	Value	Unit
144 MAPBGA	Junction to ambient, natural convection	Single layer board (1s)	θ_{JA}	53[1,2]	°C/W
	Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JA}	30[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Single layer board (1s)	θ_{JMA}	43[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	26[1,3]	°C/W
	Junction to board	—	θ_{JB}	16[4]	°C/W
	Junction to case	—	θ_{JC}	9[5]	°C/W
	Junction to top of package	Natural convection	Ψ_{jt}	2[6]	°C/W
	Maximum operating junction temperature	—	T_j	105	°C
144 LQFP	Junction to ambient, natural convection	Single layer board (1s)	θ_{JA}	44[7,8]	°C/W
	Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JA}	35[1,9]	°C/W
	Junction to ambient, (@200 ft/min)	Single layer board (1s)	θ_{JMA}	35[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	29[1,3]	°C/W
	Junction to board	—	θ_{JB}	23[10]	°C/W
	Junction to case	—	θ_{JC}	7[11]	°C/W
	Junction to top of package	Natural convection	Ψ_{jt}	2[12]	°C/W
	Maximum operating junction temperature	—	T_j	105	°C

Table 8. Thermal Characteristics (continued)

	Characteristic		Symbol	Value	Unit
100 LQFP	Junction to ambient, natural convection	Single layer board (1s)	θ_{JA}	53[13,14]	°C/W
	Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JA}	39[1,15]	°C/W
	Junction to ambient, (@200 ft/min)	Single layer board (1s)	θ_{JMA}	42[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	33[1,3]	°C/W
	Junction to board	—	θ_{JB}	25[16]	°C/W
	Junction to case	—	θ_{JC}	9[17]	°C/W
	Junction to top of package	Natural convection	Ψ_{jt}	2[18]	°C/W
	Maximum operating junction temperature	—	T_j	105	°C

1 θ_{JA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of θ_{JA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

2 Per JEDEC JESD51-2 with the single-layer board (JESD51-3) horizontal.

3 Per JEDEC JESD51-6 with the board JESD51-7) horizontal.

4 Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5 Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

6 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

7 θ_{JA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of θ_{JA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

8 Per JEDEC JESD51-2 with the single-layer board (JESD51-3) horizontal.

9 Per JEDEC JESD51-6 with the board JESD51-7) horizontal.

10 Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

11 Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

12 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

13 θ_{JA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of θ_{JA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

14 Per JEDEC JESD51-2 with the single-layer board (JESD51-3) horizontal.

15 Per JEDEC JESD51-6 with the board JESD51-7) horizontal.

[2] Reprogramming of a flash memory array block prior to erase is not required.

2.5 EzPort Electrical Specifications

Table 11. EzPort Electrical Specifications

Name	Characteristic	Min	Max	Unit
EP1	EPCK frequency of operation (all commands except READ)	—	f_{sys} / 2	MHz
EP1a	EPCK frequency of operation (READ command)	—	f_{sys} / 8	MHz
EP2	EPCS_b negation to next EPCS_b assertion	2 × T_{cyc}	—	ns
EP3	EPCS_B input valid to EPCK high (setup)	5	—	ns
EP4	EPCK high to EPCS_B input invalid (hold)	5	—	ns
EP5	EPD input valid to EPCK high (setup)	2	—	ns
EP6	EPCK high to EPD input invalid (hold)	5	—	ns
EP7	EPCK low to EPQ output valid (out setup)	—	12	ns
EP8	EPCK low to EPQ output invalid (out hold)	0	—	ns
EP9	EPCS_B negation to EPQ tri-state	—	12	ns

2.6 ESD Protection

Table 12. ESD Protection Characteristics[1, 2]

Characteristics	Symbol	Value	Units
ESD target for Human Body Model	HBM	2000	V
ESD target for Machine Model	MM	200	V
HBM circuit description	R_{series}	1500	Ω
	C	100	pF
MM circuit description	R_{series}	0	Ω
	C	200	pF
Number of pulses per pin (HBM) • Positive pulses • Negative pulses	 — —	 1 1	—
Number of pulses per pin (MM) • Positive pulses • Negative pulses	 — —	 3 3	—
Interval of pulses	—	1	sec

[1] All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.

[2] A device is defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing is performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

2.7 DC Electrical Specifications

Table 13. DC Electrical Specifications [1]

Characteristic	Symbol	Min	Max	Unit
Supply voltage	V_{DD}	3.0	3.6	V
Standby voltage	V_{STBY}	1.8	3.5	V
Input high voltage	V_{IH}	$0.7 \times V_{DD}$	4.0	V
Input low voltage	V_{IL}	$V_{SS} - 0.3$	$0.35 \times V_{DD}$	V
Input hysteresis[2]	V_{HYS}	$0.06 \times V_{DD}$	—	mV
Low-voltage detect trip voltage (V_{DD} falling)	V_{LVD}	2.15	2.3	V
Low-voltage detect hysteresis (V_{DD} rising)	V_{LVDHYS}	60	120	mV
Input leakage current $V_{in} = V_{DD}$ or V_{SS}, digital pins	I_{in}	–1.0	1.0	μA
Output high voltage (all input/output and all output pins) I_{OH} = –2.0 mA	V_{OH}	$V_{DD} - 0.5$	—	V
Output low voltage (all input/output and all output pins) I_{OL} = 2.0 mA	V_{OL}	—	0.5	V
Output high voltage (high drive) I_{OH} = -5 mA	V_{OH}	$V_{DD} - 0.5$	—	V
Output low voltage (high drive) I_{OL} = 5 mA	V_{OL}	—	0.5	V
Output high voltage (low drive) I_{OH} = -2 mA	V_{OH}	V_{DD} - 0.5	—	V
Output low voltage (low drive) I_{OL} = 2 mA	V_{OL}	—	0.5	V
Weak internal pull Up device current, tested at V_{IL} Max.[3]	I_{APU}	–10	–130	μA
Input Capacitance [4] • All input-only pins • All input/output (three-state) pins	C_{in}	 — —	 7 7	pF

1 Refer to Table 14 for additional PLL specifications.

2 Only for pins: IRQ1, IRQ3. IRQ5, IRQ7, RSTIN_B, TEST, RCON_B, PCS0, SCK, I2C_SDA, I2C_SCL, TCLK, TRST_B

3 Refer to Table 3 for pins having internal pull-up devices.

4 This parameter is characterized before qualification rather than 100% tested.

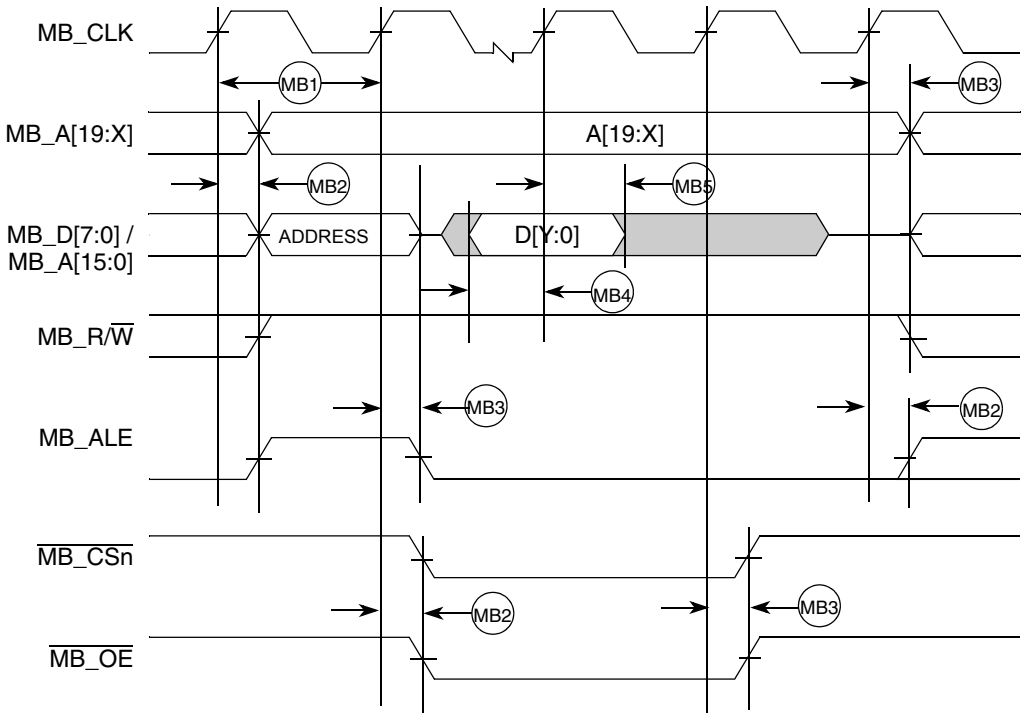


Figure 5. Mini-FlexBus Read Timing

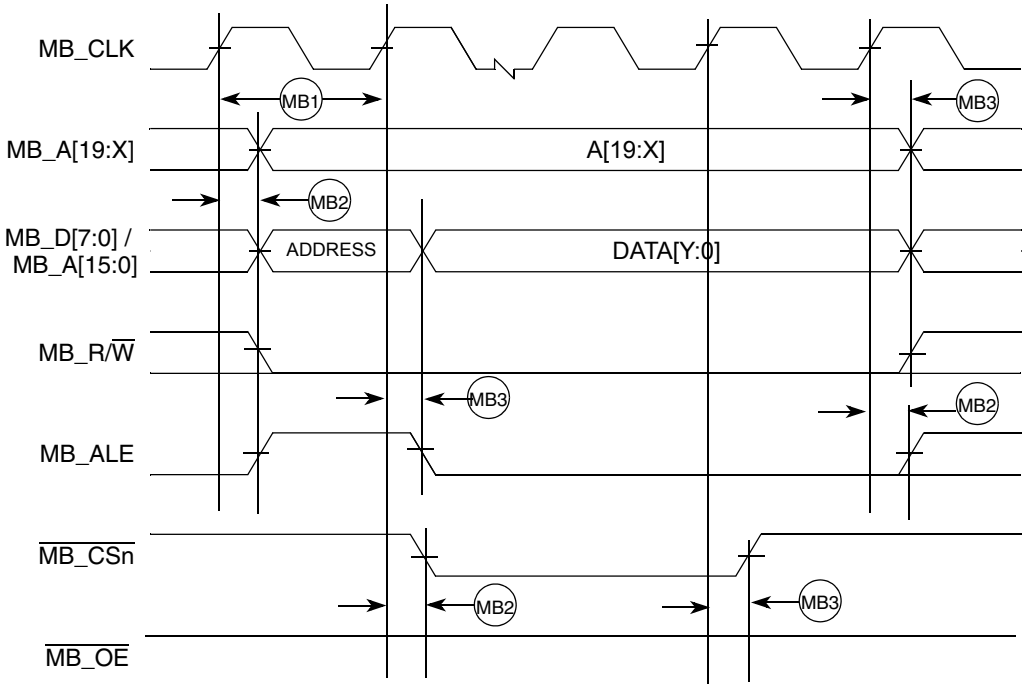


Figure 6. Mini-FlexBus Write Timing

2.11 Fast Ethernet Timing Specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface.

2.11.1 Receive Signal Timing Specifications

The following timing specs meet the requirements for MII and 7-Wire style interfaces for a range of transceiver devices.

Table 17. Receive Signal Timing

Num	Characteristic	MII Mode		Unit
		Min	Max	
—	RXCLK frequency	—	25	MHz
E1	RXD[n:0], RXDV, RXER to RXCLK setup[1]	5	—	ns
E2	RXCLK to RXD[n:0], RXDV, RXER hold[1]	5	—	ns
E3	RXCLK pulse width high	35%	65%	RXCLK period
E4	RXCLK pulse width low	35%	65%	RXCLK period

[1] In MII mode, n = 3

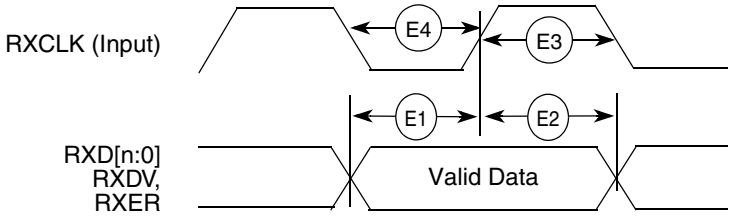


Figure 7. MII Receive Signal Timing Diagram

2.11.2 Transmit Signal Timing Specifications

Table 18. Transmit Signal Timing

Num	Characteristic	MII Mode		Unit
		Min	Max	
—	TXCLK frequency	—	25	MHz
E5	TXCLK to TXD[n:0], TXEN, TXER invalid[1]	5	—	ns
E6	TXCLK to TXD[n:0], TXEN, TXER valid[1]	—	25	ns
E7	TXCLK pulse width high	35%	65%	t_{TXCLK}
E8	TXCLK pulse width low	35%	65%	t_{TXCLK}

[1] In MII mode, n = 3

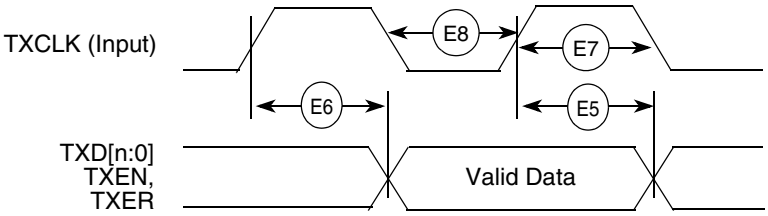


Figure 8. MII Transmit Signal Timing Diagram

2.11.3 Asynchronous Input Signal Timing Specifications

Table 19. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
E9	CRS, COL minimum pulse width	1.5	—	TXCLK period

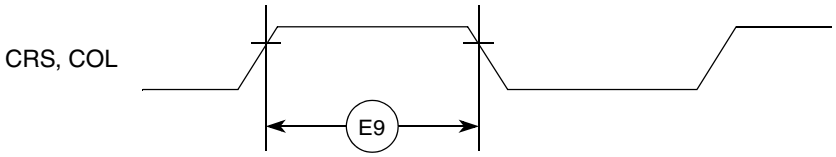


Figure 9. MII Async Inputs Timing Diagram

2.11.4 MII Serial Management Timing Specifications

Table 20. MII Serial Management Channel Signal Timing

Num	Characteristic	Symbol	Min	Max	Unit
E10	MDC cycle time	t_{MDC}	400	—	ns
E11	MDC pulse width		40	60	% t_{MDC}
E12	MDC to MDIO output valid		—	375	ns
E13	MDC to MDIO output invalid		25	—	ns
E14	MDIO input to MDC setup		10	—	ns
E15	MDIO input to MDC hold		0	—	ns

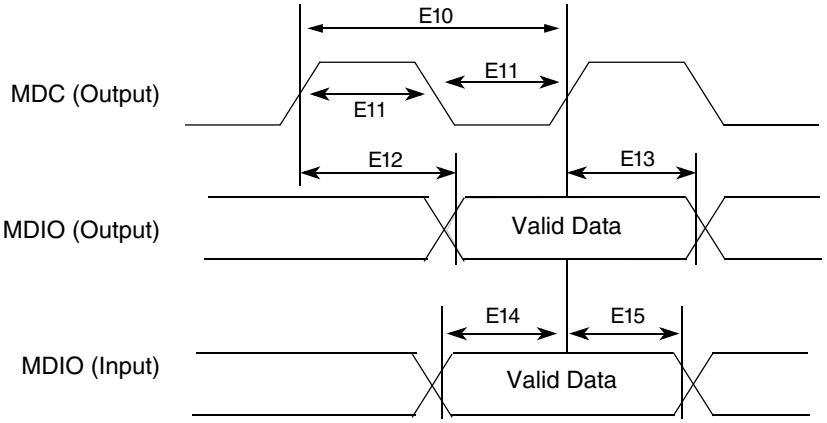


Figure 10. MII Serial Management Channel TIming Diagram

2.12 General Purpose I/O Timing

GPIO can be configured for certain pins of the QSPI, DDR Control, timer, UART, Interrupt and USB interfaces. When in GPIO mode, the timing specification for these pins is given in Table 21 and Figure 11.

The GPIO timing is met under the following load test conditions:

- 50 pF / 50 Ω for high drive

Table 25. ADC Parameters[1] (continued)

Name	Characteristic	Min	Typical	Max	Unit
SNR	Signal-to-noise ratio	—	62 to 66	—	dB
THD	Total harmonic distortion	—	–75	—	dB
SFDR	Spurious free dynamic range	—	67 to 70.3	—	dB
SINAD	Signal-to-noise plus distortion	—	61 to 63.9	—	dB
ENOB	Effective number of bits	9.1	10.6	—	Bits

1 All measurements are preliminary pending full characterization, and made at V_{DD} = 3.3 V, V_{REFH} = 3.3 V, and V_{REFL} = ground

2 INL measured from $V_{IN} = V_{REFL}$ to $V_{IN} = V_{REFH}$

3 LSB = Least Significant Bit

4 INL measured from $V_{IN} = 0.1V_{REFH}$ to $V_{IN} = 0.9V_{REFH}$

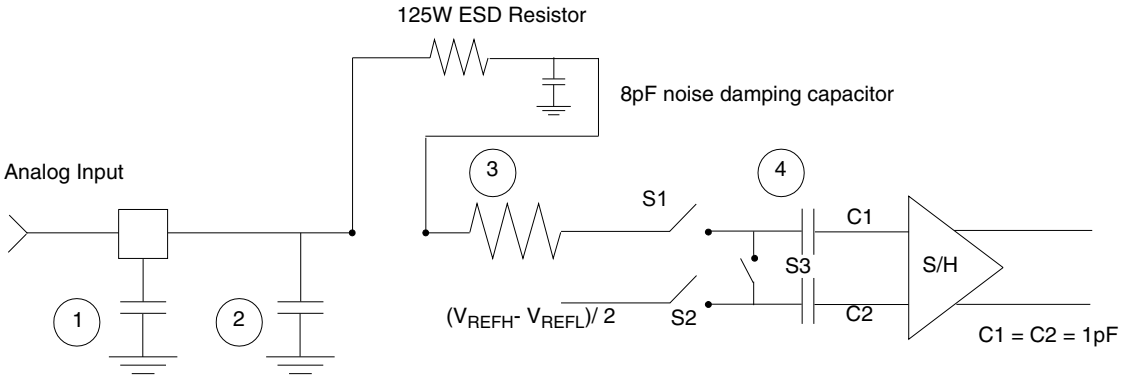
5 Includes power-up of ADC and V_{REF}

6 ADC clock cycles

7 Current that can be injected or sourced from an unselected ADC signal input without impacting the performance of the ADC

2.16 Equivalent Circuit for ADC Inputs

Figure 14 shows the ADC input circuit during sample and hold. S1 and S2 are always open/closed at the same time that S3 is closed/open. When S1/S2 are closed and S3 is open, one input of the sample and hold circuit moves to $(V_{REFH}-V_{REFL})/2$, while the other charges to the analog input voltage. When the switches are flipped, the charge on C1 and C2 are averaged via S3, with the result that a single-ended analog input is switched to a differential voltage centered about $(V_{REFH}-V_{REFL})/2$. The switches switch on every cycle of the ADC clock (open one-half ADC clock, closed one-half ADC clock). There are additional capacitances associated with the analog input pad, routing, etc., but these do not filter into the S/H output voltage, as S1 provides isolation during the charge-sharing phase. One aspect of this circuit is that there is an on-going input current, which is a function of the analog input voltage, V_{REF} and the ADC clock frequency.



1. Parasitic capacitance due to package, pin-to-pin and pin-to-package base coupling; 1.8 pF
2. Parasitic capacitance due to the chip bond pad, ESD protection devices and signal routing; 2.04 pF
3. Equivalent resistance for the channel select mux; 100 Ω
4. Sampling capacitor at the sample and hold circuit. Capacitor C1 is normally disconnected from the input and is only connected to it at sampling time; 1.4 pF
5. Equivalent input impedance, when the input is selected = $\frac{1}{(\text{ADC Clock Rate}) \times (1.4\times10^{-12})}$

Figure 14. Equivalent Circuit for A/D Loading

Table 28. JTAG and Boundary Scan Timing

Num	Characteristics[1]	Symbol	Min	Max	Unit
J1	TCLK frequency of operation	f_{JCYC}	DC	1/4	$f_{sys/2}$
J2	TCLK cycle period	t_{JCYC}	$4 \times t_{CYC}$	—	ns
J3	TCLK clock pulse width	t_{JCW}	26	—	ns
J4	TCLK rise and fall times	t_{JCRF}	0	3	ns
J5	Boundary scan input data setup time to TCLK rise	t_{BSDST}	4	—	ns
J6	Boundary scan input data hold time after TCLK rise	t_{BSDHT}	26	—	ns
J7	TCLK low to boundary scan output data valid	t_{BSDV}	0	33	ns
J8	TCLK low to boundary scan output high Z	t_{BSDZ}	0	33	ns
J9	TMS, TDI input data setup time to TCLK rise	t_{TAPBST}	4	—	ns
J10	TMS, TDI Input data hold time after TCLK rise	t_{TAPBHT}	10	—	ns
J11	TCLK low to TDO data valid	t_{TDODV}	0	26	ns
J12	TCLK low to TDO high Z	t_{TDODZ}	0	8	ns
J13	$\overline{\text{TRST}}$ assert time	t_{TRSTAT}	100	—	ns
J14	$\overline{\text{TRST}}$ setup time (negation) to TCLK high	t_{TRSTST}	10	—	ns

[1] JTAG_EN is expected to be a static signal. Hence, it is not associated with any timing.

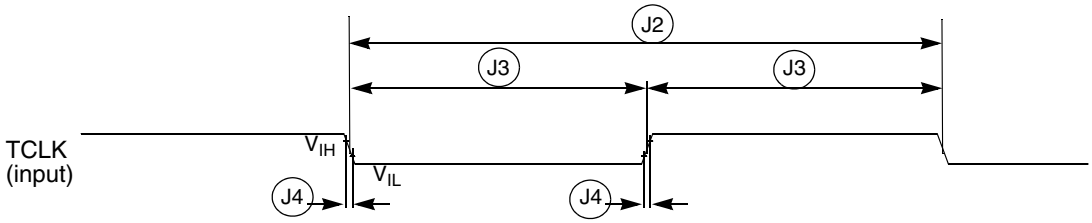


Figure 16. Test Clock Input Timing

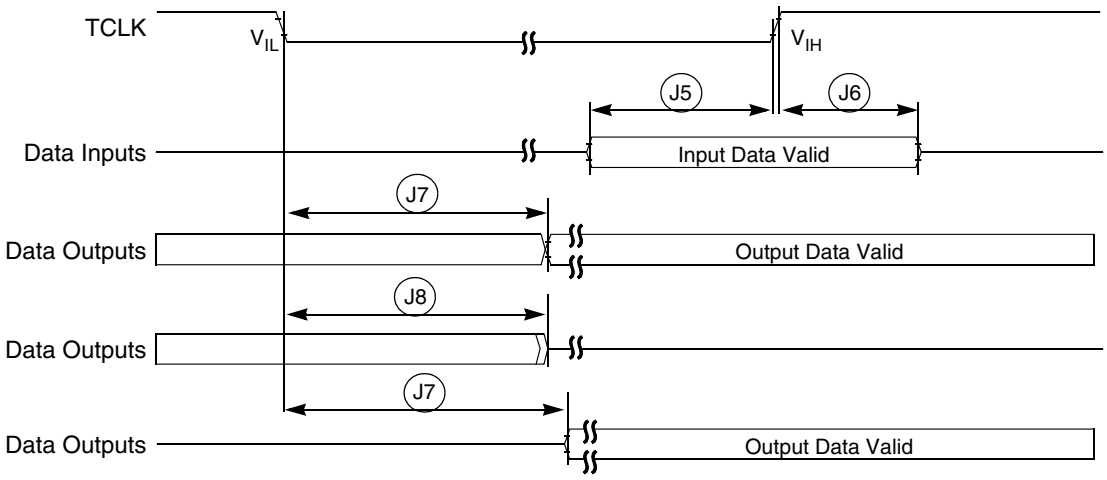


Figure 17. Boundary Scan (JTAG) Timing

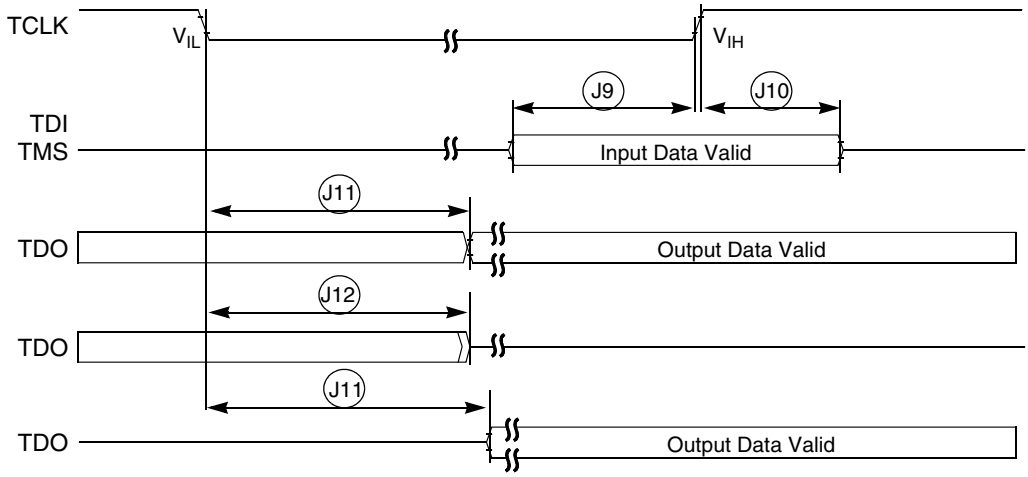


Figure 18. Test Access Port Timing

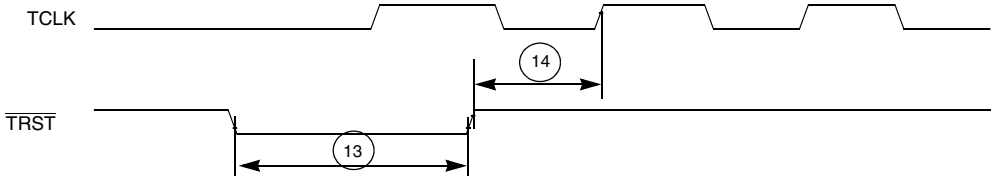


Figure 19. $\overline{TRST}$ Timing

4 Revision History

Table 31. Revision History

Revision	Description
0	Initial public release.
1	• Added package dimensions to package diagrams • Added listing of devices for MCF52259 family • Changed “Four-channel general-purpose timer (GPT) capable of input capture/output compare, pulse width modulation (PWM), and pulse accumulation” to “Four-channel general-purpose timer (GPT) capable of input capture/output compare, pulse width modulation (PWM), pulse-code modulation (PCM), and pulse accumulation” • Updated the figure **Pinout Top View (144 MAPBGA)** • Removed an extraneous instance of the table **Pin Functions by Primary and Alternate Purpose** • In the table **Pin Functions by Primary and Alternate Purpose**, changed a footnote from “This list for power and ground does not include those dedicated power/ground pins included elsewhere, such as in the ADC” to “This list for power and ground does not include those dedicated power/ground pins included elsewhere, such as in the ADC, USB, and PLL” • In the table **SGFM Flash Program and Erase Characteristics**, changed “(V_{DDF} = 2.7 to 3.6 V)“ to “(V_{DD} = 3.0 to 3.6 V)“ • In the table **SGFM Flash Module Life Characteristics**, changed “(V_{DDF} = 2.7 to 3.6 V)“ to “(V_{DD} = 3.0 to 3.6 V)“ • In the table **Oscillator and PLL Specifications**, changed “V_{DD} and V_{DDPLL} = 2.7 to 3.6 V“ to “V_{DD} and V_{DDPLL} = 3.0 to 3.6 V“ • In the table **Reset and Configuration Override Timing**, changed “V_{DD} = 2.7 to 3.6 V“ to “V_{DD} = 3.0 to 3.6 V“
2	• Added EzPort Electrical Specifications. • Updated Table 2 for part numbers. • In Table 13, added slew rate column, updated derive strength, pull-up/pull-down values,JTAG pin alternate functions, removed Wired/OR control column, and reordered AN[7:0] list of pin numbers for 144 LQFP and 100 LQFP. • Updated Table 14. • Updated Table 13, to change MIN voltage spec for Standby Voltage (VSTBY) to 1.8V (from 3.0V). • Updated Figure 2 for RTC_EXTAL and RTC_XTAL pin positions.
3	• Updated EzPort Electrical Specifications • Added hysteresis note in the DC electrical table • Clarified pin function table for VSS pins. • Clarified orderable part summary.
4	• Updated EXTAL input high voltage (External reference) Maximum to "3.0V" (Instead of "VDD"). Also, added a footnote saying, “This value has been update” • Updated crystal frequency value to 25 MHz
5	• Updated TOC

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